

Issue Classification	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/583,251	TAKEI, HIROFUMI
Examiner	Art Unit	
Heather R. Long	2615	

ISSUE CLASSIFICATION

ORIGINAL				CROSS REFERENCE(S)							
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
348		225.1									
INTERNATIONAL CLASSIFICATION											
H	0	4	N	9/73							
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<i>[Handwritten signatures and initials over rows 4-8]</i>											
<i>Heather R. Lang 8/18/05</i> (Assistant Examiner) (Date)				<i>David L. Ometz 8/19/05</i> DAVID L. OMETZ SUPERVISORY PATENT EXAMINER (Primary Examiner)				Total Claims Allowed: 15			
<i>J. Saylor 8-19-05</i> (Legal Instruments Examiner) (Date)								O.G. Print Claim(s)	O.G. Print Fig.		
								1	1		

Heather R. Long 8/18/05
(Assistant Examiner) (Date)

(Assistant Examiner) (Date)

David L. Ometz DAVID L. OMETZ 8/19/05

[Signature] (Legal Instruments Examiner) *8-19-05* (Date)

**DAVID L. UMEIZ
SUPERVISORY PATENT
EXAMINER
(Primary Examiner)**

Total Claims Allowed: 15

O.G.
Print Claim(s)
1

O.G.
Print Fig.
1

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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